

**Notice of References Cited**

Application/Control No.

10/783,554

Applicant(s)/Patent Under  
Reexamination  
LEE ET AL.

Examiner

DUSTIN NGUYEN

Art Unit

2154

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0080914	04-2005	Lerner et al.	709/230
*	B	US-2004/0117494	06-2004	Mitchell et al.	709/230
*	C	US-2007/0234417	10-2007	Blakley III et al.	726/012
*	D	US-2005/0198206	09-2005	Miller et al.	709/219
*	E	US-2005/0053007	03-2005	Bernhardt et al.	370/238
*	F	US-2008/0056500	03-2008	Bradley et al.	380/279
*	G	US-2007/0192627	08-2007	Maxted et al.	726/001
*	H	US-6,545,599	04-2003	Derbyshire et al.	340/442
*	I	US-5,845,081	12-1998	Rangarajan et al.	709/224
*	J	US-7,089,313	08-2006	Lee et al.	709/227
*	K	US-7,054,332	05-2006	Favichia et al.	370/466
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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